

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 *     Zvector E7 instruction tests for VRI-a instruction:
				5 *
				6 *     E744 VGBM    - Vector Generate Byte Mask
				7 *
				8 *             James Wekel February 2025
				9 *****
				11 *****
				12 *
				13 *             basic instruction tests
				14 *
				15 *****
				16 *     This program tests proper functioning of the z/arch E7 VRI-a
				17 *     Vector Generate Byte Mask instruction.
				18 *     Exceptions are not tested.
				19 *
				20 *     PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				21 *     obvious coding errors.   None of the tests are thorough.   They are
				22 *     NOT designed to test all aspects of any of the instructions.
				23 *
				24 *****
				25 *
				26 *     *Testcase zvector-e7-07-VGBM
				27 *     *
				28 *     *     Zvector E7 instruction tests for VRI-a instruction:
				29 *     *
				30 *     *     E744 VGBM    - Vector Generate Byte Mask
				31 *     *
				32 *     *     # -----
				33 *     *     #     This tests only the basic function of the instruction.
				34 *     *     #     Exceptions are NOT tested.
				35 *     *     # -----
				36 *     *
				37 *     main size        2
				38 *     numcpu         1
				39 *     sysclear
				40 *     archlvl        z/Arch
				41 *
				42 *     loadcore        "\$(testpath)/zvector-e7-07-VGBM core" 0x0
				43 *
				44 *     diag8cmd        enable     # (needed for messages to Hercules console)
				45 *     runtest         10         #
				46 *     diag8cmd        disable    # (reset back to default)
				47 *
				48 *     *Done
				49 *
				50 *****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				52 *****
				53 * FCHECK Macro - Is a Facility Bit set?
				54 *
				55 * If the facility bit is NOT set, an message is issued and
				56 * the test is skipped.
				57 *
				58 * Fcheck uses R0, R1 and R2
				59 *
				60 * eg. FCHECK 134, 'vector-packed-decimal'
				61 *****
				62 MACRO
				63 FCHECK &BITNO, &NOTSETMSG
				64 . * &BITNO : facility bit number to check
				65 . * &NOTSETMSG : 'facility name'
				66 LCLA &FBBYTE Facility bit in Byte
				67 LCLA &FBBIT Facility bit within Byte
				68
				69 LCLA &L(8)
				70 &L(1) SetA 128, 64, 32, 16, 8, 4, 2, 1 bit positions within byte
				71
				72 &FBBYTE SETA &BITNO/8
				73 &FBBIT SETA &L((&BITNO-(&FBBYTE*8))+1)
				74 . * MNOTE 0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'
				75
				76 B X&SYSNDX
				77 * Fcheck data area
				78 * skip messgae
				79 SKT&SYSNDX DC C' Skipping tests: '
				80 DC C&NOTSETMSG
				81 DC C' (bit &BITNO) is not installed.'
				82 SKL&SYSNDX EQU *-SKT&SYSNDX
				83 * facility bits
				84 DS FD gap
				85 FB&SYSNDX DS 4FD
				86 DS FD gap
				87 *
				88 X&SYSNDX EQU *
				89 LA R0, ((X&SYSNDX- FB&SYSNDX)/8)-1
				90 STFLE FB&SYSNDX get facility bits
				91
				92 XGR R0, R0
				93 IC R0, FB&SYSNDX+&FBBYTE get fbit byte
				94 N R0, =F' &FBBIT' is bit set?
				95 BNZ XC&SYSNDX
				96 *
				97 * facility bit not set, issue message and exit
				98 *
				99 LA R0, SKL&SYSNDX message length
				100 LA R1, SKT&SYSNDX message address
				101 BAL R2, MSG
				102
				103 B EOJ
				104 XC&SYSNDX EQU *
				105 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				107	*****
				108	* Low core PSWs
				109	*****
00000000		00000000	00001DEF	110	ZVE7TST START 0
		00000000		111	USING ZVE7TST, R0 Low core addressability
		00000140	00000000	112	
				113	SVOLDPSW EQU ZVE7TST+X' 140' z/Arch Supervisor call old PSW
00000000		00000000	000001A0	115	ORG ZVE7TST+X' 1A0' z/Architecture RESTART PSW
000001A0	00000001 80000000			116	DC X' 0000000180000000'
000001A8	00000000 00000200			117	DC AD(BEGIN)
000001B0		000001B0	000001D0	119	ORG ZVE7TST+X' 1D0' z/Architecture PROGRAM CHECK PSW
000001D0	00020001 80000000			120	DC X' 0002000180000000'
000001D8	00000000 0000DEAD			121	DC AD(X' DEAD')
000001E0		000001E0	00000200	123	ORG ZVE7TST+X' 200' Start of actual test program..
				125	*****
				126	* The actual "ZVE7TST" program itself...
				127	*****
				128	*
				129	* Architecture Mode: z/Arch
				130	* Register Usage:
				131	*
				132	* R0 (work)
				133	* R1-4 (work)
				134	* R5 Testing control table - current test base
				135	* R6- R7 (work)
				136	* R8 First base register
				137	* R9 Second base register
				138	* R10 Third base register
				139	* R11 E7TEST call return
				140	* R12 E7TESTS register
				141	* R13 (work)
				142	* R14 Subroutine call
				143	* R15 Secondary Subroutine call or work
				144	*
				145	*****
00000200		00000200		147	USING BEGIN, R8 FIRST Base Register
00000200		00001200		148	USING BEGIN+4096, R9 SECOND Base Register
00000200		00002200		149	USING BEGIN+8192, R10 THIRD Base Register
00000200	0580			151	BEGIN BALR R8, 0 Inititalize FIRST base register
00000202	0680			152	BCTR R8, 0 Inititalize FIRST base register
00000204	0680			153	BCTR R8, 0 Inititalize FIRST base register
00000206	4190 8800		00000800	155	LA R9, 2048(, R8) Inititalize SECOND base register
0000020A	4190 9800		00000800	156	LA R9, 2048(, R9) Inititalize SECOND base register
				157	





LOC	OBJECT	CODE	ADDR1	ADDR2	STMT
					225 *****
					226 * result not as expected:
					227 * issue message with test number, instruction under test
					228 * and instruction i2
					229 *****
00000304	45F0	8126	00000304	00000001	230 FAILMSG EQU *
				00000326	231 BAL R15, RPTERROR
					233 *****
					234 * continue after a failed test
					235 *****
00000308	5800	8294	00000308	00000001	236 FAILCONT EQU *
0000030C	5000	8E00		00000494	237 L R0, =F' 1' set failed test indicator
				00001000	238 ST R0, FAILED
					239
00000310	41C0	C004		00000004	240 LA R12, 4(0, R12) next test address
00000314	47F0	80D4		000002D4	241 B NEXTE6
					243 *****
					244 * end of testing; set ending psw
					245 *****
00000318	5810	8E00	00000318	00000001	246 ENDTEST EQU *
0000031C	1211			00001000	247 L R1, FAILED did a test fail?
					248 LTR R1, R1
0000031E	4780	8268		00000468	249 BZ EOJ No, exit
00000322	47F0	8280		00000480	250 B FAILTEST Yes, exit with BAD PSW

LOC	OBJECT CODE			ADDR1	ADDR2	STMT				
						252	*****			
						253	*	RPTERROR	Report instruction test in error	
						254	*****			
00000326	50F0	8188			00000388	256	RPTERROR	ST	R15, RPTSAVE	Save return address
0000032A	5050	818C			0000038C	257		ST	R5, RPTSVR5	Save R5
						258	*			
0000032E	4820	5004			00000004	259		LH	R2, TNUM	get test number and convert
00000332	4E20	8E76			00001076	260		CVD	R2, DECNUM	
00000336	D211	8E60	8E4A	00001060	0000104A	261		MVC	PRT3, EDIT	
0000033C	DE11	8E60	8E76	00001060	00001076	262		ED	PRT3, DECNUM	
00000342	D202	8E18	8E6D	00001018	0000106D	263		MVC	PRTNUM(3), PRT3+13	fill in message with test #
						264				
00000348	D207	8E33	5009	00001033	00000009	265		MVC	PRTNAME, OPNAME	fill in message with instruction
						266	*			
0000034E	4820	5007			00000007	267		LH	R2, I2	get i2 and convert
00000352	4E20	8E76			00001076	268		CVD	R2, DECNUM	
00000356	D211	8E60	8E4A	00001060	0000104A	269		MVC	PRT3, EDIT	
0000035C	DE11	8E60	8E76	00001060	00001076	270		ED	PRT3, DECNUM	
00000362	D204	8E44	8E6B	00001044	0000106B	271		MVC	PRTI2(5), PRT3+11	fill in message with i2 field
						273	*			
						274	*	Use Hercules Diagnose for Message to console		
						275	*			
00000368	9002	8190			00000390	276		STM	R0, R2, RPTDWSAV	save regs used by MSG
0000036C	4100	0042			00000042	277		LA	R0, PRTLNG	message length
00000370	4110	8E08			00001008	278		LA	R1, PRTLNE	messagfe address
00000374	4520	81A0			000003A0	279		BAL	R2, MSG	call Hercules console MSG display
00000378	9802	8190			00000390	280		LM	R0, R2, RPTDWSAV	restore regs
0000037C	5850	818C			0000038C	282		L	R5, RPTSVR5	Restore R5
00000380	58F0	8188			00000388	283		L	R15, RPTSAVE	Restore return address
00000384	07FF					284		BR	R15	Return to caller
00000388	00000000					286	RPTSAVE	DC	F' 0'	R15 save area
0000038C	00000000					287	RPTSVR5	DC	F' 0'	R5 save area
00000390	00000000	00000000				289	RPTDWSAV	DC	2D' 0'	R0- R2 save area for MSG call







LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				330 *****
				331 *            Normal completion or Abnormal termination PSWs
				332 *****
00000458	00020001 80000000			334 E0JPSW    DC        0D' 0' , X' 0002000180000000' , AD(0)
00000468	B2B2 8258		00000458	336 E0J            LPSWE E0JPSW                            Normal completion
00000470	00020001 80000000			338 FAILPSW    DC        0D' 0' , X' 0002000180000000' , AD(X' BAD' )
00000480	B2B2 8270		00000470	340 FAILTEST    LPSWE FAILPSW                            Abnormal termination
				342 *****
				343 *            Working Storage
				344 *****
00000484	00000000			346 CTLR0        DS        F                            CRO
00000488	00000000			347                DS        F
0000048C				349                LTORG ,                            Literals pool
0000048C	00000040			350                            =F' 64'
00000490	00001D6C			351                            =A(E7TESTS)
00000494	00000001			352                            =F' 1'
00000498	0000			353                            =H' 0'
0000049A	005F			354                            =AL2(L' MSGMSG)
				355
				356 *            some constants
				357
	00000400	00000001		358 K            EQU        1024                            One KB
	00001000	00000001		359 PAGE        EQU        (4*K)                            Size of one page
	00010000	00000001		360 K64        EQU        (64*K)                            64 KB
	00100000	00000001		361 MB        EQU        (K*K)                            1 MB
				362
	AABBCCDD	00000001		363 REG2PATT    EQU        X' AABBCCDD'                            Polluted Register pattern
	000000DD	00000001		364 REG2LOW    EQU                            X' DD'                            (last byte above)





LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				407	*****
				408	*            E7TEST DSECT
				409	*****
				411	E7TEST    DSECT ,
00000000	00000000			412	TSUB       DC     A(0)            pointer to test
00000004	0000			413	TNUM       DC     H' 00'           Test Number
00000006	00			414	DC     X' 00'
00000007	0000			415	I2          DC     XL2' 00'        i2 used
				416	
00000009	40404040	40404040		417	OPNAME     DC     CL8' '           E6 name
00000014	00000000			418	V2ADDR     DC     A(0)           address of v2 source
00000018	00000000			419	V3ADDR     DC     A(0)           address of v3 source
0000001C	00000000			420	RELEN       DC     A(0)           RESULT LENGTH
00000020	00000000			421	READDR     DC     A(0)           result (expected) address
00000028	00000000	00000000		422	DS     FD            gap
00000030	00000000	00000000		423	V10OUTPUT   DS     XL16          V1 Output
00000040	00000000	00000000		424	DS     FD            gap
				425	
				426	*            test routine will be here (from VRI-a macro)
				427	*
				428	*            followed by
				429	*            EXPECTED RESULT
				431	ZVE7TST    CSECT ,
000010B8		00000000	00001DEF	432	DS     0F
				434	*****
				435	*            Macros to help build test tables
				436	*****
				438	*
				439	*            macro to generate individual test
				440	*
				441	MACRO
				442	VRI_A &INST, &I2
				443	. *                                &INST    - VRI-a instruction under test
				444	. *                                &i2        - i2 mask field
				445	
				446	GBLA    &TNUM
				447	&TNUM       SETA    &TNUM+1
				448	
				449	DS     0FD
				450	USING       *, R5                base for test data and test routine
				451	
				452	T&TNUM     DC     A(X&TNUM)       address of test routine
				453	DC     H' &TNUM       test number
				454	DC     X' 00'
				455	DC     XL2' &I2'        i2
				456	DC     CL8' &INST'     instruction name
				457	DC     A(RE&TNUM+16)   address of v2 source



LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				502 *****	
				503 * E6 VRI-a tests	
				504 *****	
				505 PRINT DATA	
				506 *	
				507 * E744 VGBM - Vector Generate Byte Mask	
				508 *	
				509 * VRI-a instruction, I2 (immediate in HEX)	
				510 * followed by	
				511 * 16 byte expected result (V1)	
				512 * -----	
				513 * VGBM - Vector Generate Byte Mask	
				514 * -----	
				515 * -----	
				516 * case 0 - simple, simple debug	
				517 * -----	
				518 VRI_A VGBM, 0000	
000010B8				519+ DS OFD	
000010B8		000010B8		520+ USING *, R5	base for test data and test routine
000010B8	00001100			521+T1 DC A(X1)	address of test routine
000010BC	0001			522+ DC H' 1'	test number
000010BE	00			523+ DC X' 00'	
000010BF	0000			524+ DC XL2' 0000'	i2
000010C1	E5C7C2D4 40404040			525+ DC CL8' VGBM	instruction name
000010CC	00001124			526+ DC A(RE1+16)	address of v2 source
000010D0	00001134			527+ DC A(RE1+32)	address of v3 source
000010D4	00000010			528+ DC A(16)	result length
000010D8	00001114			529+REA1 DC A(RE1)	result address
000010E0	00000000 00000000			530+ DS FD	gap
000010E8	00000000 00000000			531+V101 DS XL16	V1 output
000010F0	00000000 00000000				
000010F8	00000000 00000000			532+ DS FD	gap
				533+ *	
00001100				534+X1 DS OF	
00001100	E760 8E98 0806		00001098	535+ VL V22, V1FUDGE	
00001106	E760 0000 0844			536+ VGBM V22, X' 0000'	test instruction (dest is a source)
0000110C	E760 5030 080E		000010E8	537+ VST V22, V101	save v1 output
00001112	07FB			538+ BR R11	return
00001114				539+RE1 DC OF	xl16 expected result
00001114				540+ DROP R5	
00001114	00000000 00000000			541 DC XL16' 00000000 00000000 00000000 00000000'	expected mask
0000111C	00000000 00000000				
				542	
				543 VRI_A VGBM, 0001	
00001128				544+ DS OFD	
00001128		00001128		545+ USING *, R5	base for test data and test routine
00001128	00001170			546+T2 DC A(X2)	address of test routine
0000112C	0002			547+ DC H' 2'	test number
0000112E	00			548+ DC X' 00'	
0000112F	0001			549+ DC XL2' 0001'	i2
00001131	E5C7C2D4 40404040			550+ DC CL8' VGBM	instruction name
0000113C	00001194			551+ DC A(RE2+16)	address of v2 source
00001140	000011A4			552+ DC A(RE2+32)	address of v3 source
00001144	00000010			553+ DC A(16)	result length
00001148	00001184			554+REA2 DC A(RE2)	result address
00001150	00000000 00000000			555+ DS FD	gap

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001158	00000000 00000000			556+V102	DS	XL16	V1 output
00001160	00000000 00000000						
00001168	00000000 00000000			557+	DS	FD	gap
				558+*			
00001170				559+X2	DS	0F	
00001170	E760 8E98 0806		00001098	560+	VL	V22, V1FUDGE	
00001176	E760 0001 0844			561+	VGBM	V22, X' 0001'	test instruction (dest is a source)
0000117C	E760 5030 080E		00001158	562+	VST	V22, V102	save v1 output
00001182	07FB			563+	BR	R11	return
00001184				564+RE2	DC	0F	xl16 expected result
00001184				565+	DROP	R5	
00001184	00000000 00000000			566	DC	XL16' 00000000 00000000 00000000 000000FF'	expected mask
0000118C	00000000 000000FF						
				567			
				568	VRI_A	VGBM, 0002	
00001198				569+	DS	0FD	
00001198		00001198		570+	USING	*, R5	base for test data and test routine
00001198	000011E0			571+T3	DC	A(X3)	address of test routine
0000119C	0003			572+	DC	H' 3'	test number
0000119E	00			573+	DC	X' 00'	
0000119F	0002			574+	DC	XL2' 0002'	i2
000011A1	E5C7C2D4 40404040			575+	DC	CL8' VGBM	instruction name
000011AC	00001204			576+	DC	A(RE3+16)	address of v2 source
000011B0	00001214			577+	DC	A(RE3+32)	address of v3 source
000011B4	00000010			578+	DC	A(16)	result length
000011B8	000011F4			579+REA3	DC	A(RE3)	result address
000011C0	00000000 00000000			580+	DS	FD	gap
000011C8	00000000 00000000			581+V103	DS	XL16	V1 output
000011D0	00000000 00000000						
000011D8	00000000 00000000			582+	DS	FD	gap
				583+*			
000011E0				584+X3	DS	0F	
000011E0	E760 8E98 0806		00001098	585+	VL	V22, V1FUDGE	
000011E6	E760 0002 0844			586+	VGBM	V22, X' 0002'	test instruction (dest is a source)
000011EC	E760 5030 080E		000011C8	587+	VST	V22, V103	save v1 output
000011F2	07FB			588+	BR	R11	return
000011F4				589+RE3	DC	0F	xl16 expected result
000011F4				590+	DROP	R5	
000011F4	00000000 00000000			591	DC	XL16' 00000000 00000000 00000000 0000FF00'	expected mask
000011FC	00000000 0000FF00						
				592			
				593	VRI_A	VGBM, 0004	
00001208				594+	DS	0FD	
00001208		00001208		595+	USING	*, R5	base for test data and test routine
00001208	00001250			596+T4	DC	A(X4)	address of test routine
0000120C	0004			597+	DC	H' 4'	test number
0000120E	00			598+	DC	X' 00'	
0000120F	0004			599+	DC	XL2' 0004'	i2
00001211	E5C7C2D4 40404040			600+	DC	CL8' VGBM	instruction name
0000121C	00001274			601+	DC	A(RE4+16)	address of v2 source
00001220	00001284			602+	DC	A(RE4+32)	address of v3 source
00001224	00000010			603+	DC	A(16)	result length
00001228	00001264			604+REA4	DC	A(RE4)	result address
00001230	00000000 00000000			605+	DS	FD	gap
00001238	00000000 00000000			606+V104	DS	XL16	V1 output
00001240	00000000 00000000						



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001248	00000000 00000000			607+ 608+*	DS	FD	gap
00001250				609+X4	DS	0F	
00001250	E760 8E98 0806		00001098	610+	VL	V22, V1FUDGE	
00001256	E760 0004 0844			611+	VGBM	V22, X' 0004'	test instruction (dest is a source)
0000125C	E760 5030 080E		00001238	612+	VST	V22, V104	save v1 output
00001262	07FB			613+	BR	R11	return
00001264				614+RE4	DC	0F	xl16 expected result
00001264				615+	DROP	R5	
00001264	00000000 00000000			616	DC	XL16' 00000000 00000000 00000000 00FF0000'	expected mask
0000126C	00000000 00FF0000						
00001278				617			
00001278				618	VRI_A	VGBM, 0008	
00001278		00001278		619+	DS	0FD	
00001278	000012C0			620+	USING	*, R5	base for test data and test routine
0000127C	0005			621+T5	DC	A(X5)	address of test routine
0000127E	00			622+	DC	H' 5'	test number
0000127F	0008			623+	DC	X' 00'	
00001281	E5C7C2D4 40404040			624+	DC	XL2' 0008'	i2
0000128C	000012E4			625+	DC	CL8' VGBM	instruction name
00001290	000012F4			626+	DC	A(RE5+16)	address of v2 source
00001294	00000010			627+	DC	A(RE5+32)	address of v3 source
00001298	000012D4			628+	DC	A(16)	result length
00001298				629+REA5	DC	A(RE5)	result address
000012A0	00000000 00000000			630+	DS	FD	gap
000012A8	00000000 00000000			631+V105	DS	XL16	V1 output
000012B0	00000000 00000000						
000012B8	00000000 00000000			632+	DS	FD	gap
000012C0				633+*			
000012C0	E760 8E98 0806		00001098	634+X5	DS	0F	
000012C6	E760 0008 0844			635+	VL	V22, V1FUDGE	
000012CC	E760 5030 080E		000012A8	636+	VGBM	V22, X' 0008'	test instruction (dest is a source)
000012D2	07FB			637+	VST	V22, V105	save v1 output
000012D4				638+	BR	R11	return
000012D4				639+RE5	DC	0F	xl16 expected result
000012D4				640+	DROP	R5	
000012D4	00000000 00000000			641	DC	XL16' 00000000 00000000 00000000 FF000000'	expected mask
000012DC	00000000 FF000000						
000012E8				642			
000012E8				643	VRI_A	VGBM, 0010	
000012E8		000012E8		644+	DS	0FD	
000012E8	00001330			645+	USING	*, R5	base for test data and test routine
000012EC	0006			646+T6	DC	A(X6)	address of test routine
000012EE	00			647+	DC	H' 6'	test number
000012EF	0010			648+	DC	X' 00'	
000012F1	E5C7C2D4 40404040			649+	DC	XL2' 0010'	i2
000012FC	00001354			650+	DC	CL8' VGBM	instruction name
00001300	00001364			651+	DC	A(RE6+16)	address of v2 source
00001304	00000010			652+	DC	A(RE6+32)	address of v3 source
00001308	00001344			653+	DC	A(16)	result length
00001308				654+REA6	DC	A(RE6)	result address
00001310	00000000 00000000			655+	DS	FD	gap
00001318	00000000 00000000			656+V106	DS	XL16	V1 output
00001320	00000000 00000000						
00001328	00000000 00000000			657+	DS	FD	gap
				658+*			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001330				659+X6	DS	0F	
00001330	E760 8E98 0806		00001098	660+	VL	V22, V1FUDGE	
00001336	E760 0010 0844			661+	VGBM	V22, X' 0010'	test instruction (dest is a source)
0000133C	E760 5030 080E		00001318	662+	VST	V22, V106	save v1 output
00001342	07FB			663+	BR	R11	return
00001344				664+RE6	DC	0F	xl16 expected result
00001344				665+	DROP	R5	
00001344	00000000 00000000			666	DC	XL16' 00000000 00000000 000000FF 00000000'	expected mask
0000134C	000000FF 00000000						
				667			
				668	VRI_A	VGBM, 0020	
00001358				669+	DS	0FD	
00001358		00001358		670+	USING	*, R5	base for test data and test routine
00001358	000013A0			671+T7	DC	A(X7)	address of test routine
0000135C	0007			672+	DC	H' 7'	test number
0000135E	00			673+	DC	X' 00'	
0000135F	0020			674+	DC	XL2' 0020'	i2
00001361	E5C7C2D4 40404040			675+	DC	CL8' VGBM	instruction name
0000136C	000013C4			676+	DC	A(RE7+16)	address of v2 source
00001370	000013D4			677+	DC	A(RE7+32)	address of v3 source
00001374	00000010			678+	DC	A(16)	result length
00001378	000013B4			679+REA7	DC	A(RE7)	result address
00001380	00000000 00000000			680+	DS	FD	gap
00001388	00000000 00000000			681+V107	DS	XL16	V1 output
00001390	00000000 00000000						
00001398	00000000 00000000			682+	DS	FD	gap
				683+*			
000013A0				684+X7	DS	0F	
000013A0	E760 8E98 0806		00001098	685+	VL	V22, V1FUDGE	
000013A6	E760 0020 0844			686+	VGBM	V22, X' 0020'	test instruction (dest is a source)
000013AC	E760 5030 080E		00001388	687+	VST	V22, V107	save v1 output
000013B2	07FB			688+	BR	R11	return
000013B4				689+RE7	DC	0F	xl16 expected result
000013B4				690+	DROP	R5	
000013B4	00000000 00000000			691	DC	XL16' 00000000 00000000 0000FF00 00000000'	expected mask
000013BC	0000FF00 00000000						
				692			
				693	VRI_A	VGBM, 0040	
000013C8				694+	DS	0FD	
000013C8		000013C8		695+	USING	*, R5	base for test data and test routine
000013C8	00001410			696+T8	DC	A(X8)	address of test routine
000013CC	0008			697+	DC	H' 8'	test number
000013CE	00			698+	DC	X' 00'	
000013CF	0040			699+	DC	XL2' 0040'	i2
000013D1	E5C7C2D4 40404040			700+	DC	CL8' VGBM	instruction name
000013DC	00001434			701+	DC	A(RE8+16)	address of v2 source
000013E0	00001444			702+	DC	A(RE8+32)	address of v3 source
000013E4	00000010			703+	DC	A(16)	result length
000013E8	00001424			704+REA8	DC	A(RE8)	result address
000013F0	00000000 00000000			705+	DS	FD	gap
000013F8	00000000 00000000			706+V108	DS	XL16	V1 output
00001400	00000000 00000000						
00001408	00000000 00000000			707+	DS	FD	gap
				708+*			
00001410				709+X8	DS	0F	
00001410	E760 8E98 0806		00001098	710+	VL	V22, V1FUDGE	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001416	E760 0040 0844			711+	VGBM	V22, X' 0040'	test instruction (dest is a source)
0000141C	E760 5030 080E		000013F8	712+	VST	V22, V108	save v1 output
00001422	07FB			713+	BR	R11	return
00001424				714+RE8	DC	0F	xl16 expected result
00001424				715+	DROP	R5	
00001424	00000000 00000000			716	DC	XL16' 00000000 00000000 00FF0000 00000000'	expected mask
0000142C	00FF0000 00000000						
				717			
00001438				718	VRI_A	VGBM, 0080	
00001438		00001438		719+	DS	0FD	
00001438	00001480			720+	USING	*, R5	base for test data and test routine
0000143C	0009			721+T9	DC	A(X9)	address of test routine
0000143E	00			722+	DC	H' 9'	test number
0000143E	00			723+	DC	X' 00'	
0000143F	0080			724+	DC	XL2' 0080'	i2
00001441	E5C7C2D4 40404040			725+	DC	CL8' VGBM	instruction name
0000144C	000014A4			726+	DC	A(RE9+16)	address of v2 source
00001450	000014B4			727+	DC	A(RE9+32)	address of v3 source
00001454	00000010			728+	DC	A(16)	result length
00001458	00001494			729+REA9	DC	A(RE9)	result address
00001460	00000000 00000000			730+	DS	FD	gap
00001468	00000000 00000000			731+V109	DS	XL16	V1 output
00001470	00000000 00000000						
00001478	00000000 00000000			732+	DS	FD	gap
				733+*			
00001480				734+X9	DS	0F	
00001480	E760 8E98 0806		00001098	735+	VL	V22, V1FUDGE	
00001486	E760 0080 0844			736+	VGBM	V22, X' 0080'	test instruction (dest is a source)
0000148C	E760 5030 080E		00001468	737+	VST	V22, V109	save v1 output
00001492	07FB			738+	BR	R11	return
00001494				739+RE9	DC	0F	xl16 expected result
00001494				740+	DROP	R5	
00001494	00000000 00000000			741	DC	XL16' 00000000 00000000 FF000000 00000000'	expected mask
0000149C	FF000000 00000000						
				742			
000014A8				743	VRI_A	VGBM, 0100	
000014A8		000014A8		744+	DS	0FD	
000014A8	000014F0			745+	USING	*, R5	base for test data and test routine
000014AC	000A			746+T10	DC	A(X10)	address of test routine
000014AE	00			747+	DC	H' 10'	test number
000014AE	00			748+	DC	X' 00'	
000014AF	0100			749+	DC	XL2' 0100'	i2
000014B1	E5C7C2D4 40404040			750+	DC	CL8' VGBM	instruction name
000014BC	00001514			751+	DC	A(RE10+16)	address of v2 source
000014C0	00001524			752+	DC	A(RE10+32)	address of v3 source
000014C4	00000010			753+	DC	A(16)	result length
000014C8	00001504			754+REA10	DC	A(RE10)	result address
000014D0	00000000 00000000			755+	DS	FD	gap
000014D8	00000000 00000000			756+V1010	DS	XL16	V1 output
000014E0	00000000 00000000						
000014E8	00000000 00000000			757+	DS	FD	gap
				758+*			
000014F0				759+X10	DS	0F	
000014F0	E760 8E98 0806		00001098	760+	VL	V22, V1FUDGE	
000014F6	E760 0100 0844			761+	VGBM	V22, X' 0100'	test instruction (dest is a source)
000014FC	E760 5030 080E		000014D8	762+	VST	V22, V1010	save v1 output

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001502	07FB			763+	BR	R11	return
00001504				764+RE10	DC	0F	xl16 expected result
00001504				765+	DROP	R5	
00001504	00000000 000000FF			766	DC	XL16' 00000000 000000FF 00000000 00000000'	expected mask
0000150C	00000000 00000000						
				767			
				768	VRI_A	VGBM, 0200	
00001518				769+	DS	0FD	
00001518		00001518		770+	USING	*, R5	base for test data and test routine
00001518	00001560			771+T11	DC	A(X11)	address of test routine
0000151C	000B			772+	DC	H' 11'	test number
0000151E	00			773+	DC	X' 00'	
0000151F	0200			774+	DC	XL2' 0200'	i2
00001521	E5C7C2D4 40404040			775+	DC	CL8' VGBM	instruction name
0000152C	00001584			776+	DC	A(RE11+16)	address of v2 source
00001530	00001594			777+	DC	A(RE11+32)	address of v3 source
00001534	00000010			778+	DC	A(16)	result length
00001538	00001574			779+REA11	DC	A(RE11)	result address
00001540	00000000 00000000			780+	DS	FD	gap
00001548	00000000 00000000			781+V1011	DS	XL16	V1 output
00001550	00000000 00000000						
00001558	00000000 00000000			782+	DS	FD	gap
				783+*			
00001560				784+X11	DS	0F	
00001560	E760 8E98 0806		00001098	785+	VL	V22, V1FUDGE	
00001566	E760 0200 0844			786+	VGBM	V22, X' 0200'	test instruction (dest is a source)
0000156C	E760 5030 080E		00001548	787+	VST	V22, V1011	save v1 output
00001572	07FB			788+	BR	R11	return
00001574				789+RE11	DC	0F	xl16 expected result
00001574				790+	DROP	R5	
00001574	00000000 0000FF00			791	DC	XL16' 00000000 0000FF00 00000000 00000000'	expected mask
0000157C	00000000 00000000						
				792			
				793	VRI_A	VGBM, 0400	
00001588				794+	DS	0FD	
00001588		00001588		795+	USING	*, R5	base for test data and test routine
00001588	000015D0			796+T12	DC	A(X12)	address of test routine
0000158C	000C			797+	DC	H' 12'	test number
0000158E	00			798+	DC	X' 00'	
0000158F	0400			799+	DC	XL2' 0400'	i2
00001591	E5C7C2D4 40404040			800+	DC	CL8' VGBM	instruction name
0000159C	000015F4			801+	DC	A(RE12+16)	address of v2 source
000015A0	00001604			802+	DC	A(RE12+32)	address of v3 source
000015A4	00000010			803+	DC	A(16)	result length
000015A8	000015E4			804+REA12	DC	A(RE12)	result address
000015B0	00000000 00000000			805+	DS	FD	gap
000015B8	00000000 00000000			806+V1012	DS	XL16	V1 output
000015C0	00000000 00000000						
000015C8	00000000 00000000			807+	DS	FD	gap
				808+*			
000015D0				809+X12	DS	0F	
000015D0	E760 8E98 0806		00001098	810+	VL	V22, V1FUDGE	
000015D6	E760 0400 0844			811+	VGBM	V22, X' 0400'	test instruction (dest is a source)
000015DC	E760 5030 080E		000015B8	812+	VST	V22, V1012	save v1 output
000015E2	07FB			813+	BR	R11	return
000015E4				814+RE12	DC	0F	xl16 expected result





LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000016CC	00000000 00000000			867		
				868	VRI_A VGBM, 2000	
000016D8				869+	DS OFD	
000016D8		000016D8		870+	USING *, R5	base for test data and test routine
000016D8	00001720			871+T15	DC A(X15)	address of test routine
000016DC	000F			872+	DC H' 15'	test number
000016DE	00			873+	DC X' 00'	
000016DF	2000			874+	DC XL2' 2000'	i2
000016E1	E5C7C2D4 40404040			875+	DC CL8' VGBM	instruction name
000016EC	00001744			876+	DC A(RE15+16)	address of v2 source
000016F0	00001754			877+	DC A(RE15+32)	address of v3 source
000016F4	00000010			878+	DC A(16)	result length
000016F8	00001734			879+REA15	DC A(RE15)	result address
00001700	00000000 00000000			880+	DS FD	gap
00001708	00000000 00000000			881+V1015	DS XL16	V1 output
00001710	00000000 00000000					
00001718	00000000 00000000			882+	DS FD	gap
				883+*		
00001720				884+X15	DS OF	
00001720	E760 8E98 0806		00001098	885+	VL V22, V1FUDGE	
00001726	E760 2000 0844			886+	VGBM V22, X' 2000'	test instruction (dest is a source)
0000172C	E760 5030 080E		00001708	887+	VST V22, V1015	save v1 output
00001732	07FB			888+	BR R11	return
00001734				889+RE15	DC OF	xl16 expected result
00001734				890+	DROP R5	
00001734	0000FF00 00000000			891	DC XL16' 0000FF00 00000000 00000000 00000000'	expected mask
0000173C	00000000 00000000					
				892		
				893	VRI_A VGBM, 4000	
00001748				894+	DS OFD	
00001748		00001748		895+	USING *, R5	base for test data and test routine
00001748	00001790			896+T16	DC A(X16)	address of test routine
0000174C	0010			897+	DC H' 16'	test number
0000174E	00			898+	DC X' 00'	
0000174F	4000			899+	DC XL2' 4000'	i2
00001751	E5C7C2D4 40404040			900+	DC CL8' VGBM	instruction name
0000175C	000017B4			901+	DC A(RE16+16)	address of v2 source
00001760	000017C4			902+	DC A(RE16+32)	address of v3 source
00001764	00000010			903+	DC A(16)	result length
00001768	000017A4			904+REA16	DC A(RE16)	result address
00001770	00000000 00000000			905+	DS FD	gap
00001778	00000000 00000000			906+V1016	DS XL16	V1 output
00001780	00000000 00000000					
00001788	00000000 00000000			907+	DS FD	gap
				908+*		
00001790				909+X16	DS OF	
00001790	E760 8E98 0806		00001098	910+	VL V22, V1FUDGE	
00001796	E760 4000 0844			911+	VGBM V22, X' 4000'	test instruction (dest is a source)
0000179C	E760 5030 080E		00001778	912+	VST V22, V1016	save v1 output
000017A2	07FB			913+	BR R11	return
000017A4				914+RE16	DC OF	xl16 expected result
000017A4				915+	DROP R5	
000017A4	00FF0000 00000000			916	DC XL16' 00FF0000 00000000 00000000 00000000'	expected mask
000017AC	00000000 00000000					
				917		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				918	VRI_A VGBM, 8000	
000017B8				919+	DS OFD	
000017B8		000017B8		920+	USING *, R5	base for test data and test routine
000017B8	00001800			921+T17	DC A(X17)	address of test routine
000017BC	0011			922+	DC H' 17'	test number
000017BE	00			923+	DC X' 00'	
000017BF	8000			924+	DC XL2' 8000'	i2
000017C1	E5C7C2D4 40404040			925+	DC CL8' VGBM	instruction name
000017CC	00001824			926+	DC A(RE17+16)	address of v2 source
000017D0	00001834			927+	DC A(RE17+32)	address of v3 source
000017D4	00000010			928+	DC A(16)	result length
000017D8	00001814			929+REA17	DC A(RE17)	result address
000017E0	00000000 00000000			930+	DS FD	gap
000017E8	00000000 00000000			931+V1017	DS XL16	V1 output
000017F0	00000000 00000000					
000017F8	00000000 00000000			932+	DS FD	gap
				933+*		
00001800				934+X17	DS OF	
00001800	E760 8E98 0806		00001098	935+	VL V22, V1FUDGE	
00001806	E760 8000 0844			936+	VGBM V22, X' 8000'	test instruction (dest is a source)
0000180C	E760 5030 080E		000017E8	937+	VST V22, V1017	save v1 output
00001812	07FB			938+	BR R11	return
00001814				939+RE17	DC OF	xl16 expected result
00001814				940+	DROP R5	
00001814	FF000000 00000000			941	DC XL16' FF000000 00000000 00000000 00000000'	expected mask
0000181C	00000000 00000000					
				942		
				943	VRI_A VGBM, FFFF	
00001828				944+	DS OFD	
00001828		00001828		945+	USING *, R5	base for test data and test routine
00001828	00001870			946+T18	DC A(X18)	address of test routine
0000182C	0012			947+	DC H' 18'	test number
0000182E	00			948+	DC X' 00'	
0000182F	FFFF			949+	DC XL2' FFFF'	i2
00001831	E5C7C2D4 40404040			950+	DC CL8' VGBM	instruction name
0000183C	00001894			951+	DC A(RE18+16)	address of v2 source
00001840	000018A4			952+	DC A(RE18+32)	address of v3 source
00001844	00000010			953+	DC A(16)	result length
00001848	00001884			954+REA18	DC A(RE18)	result address
00001850	00000000 00000000			955+	DS FD	gap
00001858	00000000 00000000			956+V1018	DS XL16	V1 output
00001860	00000000 00000000					
00001868	00000000 00000000			957+	DS FD	gap
				958+*		
00001870				959+X18	DS OF	
00001870	E760 8E98 0806		00001098	960+	VL V22, V1FUDGE	
00001876	E760 FFFF 0844			961+	VGBM V22, X' FFFF'	test instruction (dest is a source)
0000187C	E760 5030 080E		00001858	962+	VST V22, V1018	save v1 output
00001882	07FB			963+	BR R11	return
00001884				964+RE18	DC OF	xl16 expected result
00001884				965+	DROP R5	
00001884	FFFFFFFF FFFFFFFF			966	DC XL16' FFFFFFFFFF FFFFFFFFFF FFFFFFFFFF FFFFFFFFFF'	expected mask
0000188C	FFFFFFFF FFFFFFFF					



LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				968 *	-----
				969 *	case 1 - multiple bits
				970 *	-----
00001898				971	VRI_A VGBM 8001
00001898		00001898		972+	DS OFD
00001898	000018E0			973+	USING *, R5
0000189C	0013			974+T19	DC A(X19)
0000189E	00			975+	DC H' 19'
0000189F	8001			976+	DC X' 00'
000018A1	E5C7C2D4 40404040			977+	DC XL2' 8001'
000018AC	00001904			978+	DC CL8' VGBM
000018B0	00001914			979+	DC A(RE19+16)
000018B4	00000010			980+	DC A(RE19+32)
000018B8	000018F4			981+	DC A(16)
000018C0	00000000 00000000			982+REA19	DC A(RE19)
000018C8	00000000 00000000			983+	DS FD
000018D0	00000000 00000000			984+V1019	DS XL16
000018D8	00000000 00000000			985+	DS FD
				986+*	gap
000018E0				987+X19	DS OF
000018E0	E760 8E98 0806		00001098	988+	VL V22, V1FUDGE
000018E6	E760 8001 0844			989+	VGBM V22, X' 8001'
000018EC	E760 5030 080E		000018C8	990+	VST V22, V1019
000018F2	07FB			991+	BR R11
000018F4				992+RE19	DC OF
000018F4				993+	DROP R5
000018F4	FF000000 00000000			994	DC XL16' FF000000 00000000 00000000 000000FF' expected mask
000018FC	00000000 000000FF				
				995	
00001908				996	VRI_A VGBM 8181
00001908		00001908		997+	DS OFD
00001908	00001950			998+	USING *, R5
0000190C	0014			999+T20	DC A(X20)
0000190E	00			1000+	DC H' 20'
0000190F	8181			1001+	DC X' 00'
00001911	E5C7C2D4 40404040			1002+	DC XL2' 8181'
0000191C	00001974			1003+	DC CL8' VGBM
00001920	00001984			1004+	DC A(RE20+16)
00001924	00000010			1005+	DC A(RE20+32)
00001928	00001964			1006+	DC A(16)
00001930	00000000 00000000			1007+REA20	DC A(RE20)
00001938	00000000 00000000			1008+	DS FD
00001940	00000000 00000000			1009+V1020	DS XL16
00001948	00000000 00000000			1010+	DS FD
				1011+*	gap
00001950				1012+X20	DS OF
00001950	E760 8E98 0806		00001098	1013+	VL V22, V1FUDGE
00001956	E760 8181 0844			1014+	VGBM V22, X' 8181'
0000195C	E760 5030 080E		00001938	1015+	VST V22, V1020
00001962	07FB			1016+	BR R11
00001964				1017+RE20	DC OF
00001964				1018+	DROP R5
00001964	FF000000 000000FF			1019	DC XL16' FF000000 000000FF FF000000 000000FF' expected mask
0000196C	FF000000 000000FF				

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				1020		
				1021	VRI_A	VGBM, 1818
00001978				1022+	DS	OFD
00001978		00001978		1023+	USING	*, R5
00001978	000019C0			1024+T21	DC	A(X21)
0000197C	0015			1025+	DC	H' 21'
0000197E	00			1026+	DC	X' 00'
0000197F	1818			1027+	DC	XL2' 1818'
00001981	E5C7C2D4 40404040			1028+	DC	CL8' VGBM
0000198C	000019E4			1029+	DC	A(RE21+16)
00001990	000019F4			1030+	DC	A(RE21+32)
00001994	00000010			1031+	DC	A(16)
00001998	000019D4			1032+REA21	DC	A(RE21)
000019A0	00000000 00000000			1033+	DS	FD
000019A8	00000000 00000000			1034+V1021	DS	XL16
000019B0	00000000 00000000					
000019B8	00000000 00000000			1035+	DS	FD
				1036+*		gap
000019C0				1037+X21	DS	OF
000019C0	E760 8E98 0806		00001098	1038+	VL	V22, V1FUDGE
000019C6	E760 1818 0844			1039+	VGBM	V22, X' 1818'
000019CC	E760 5030 080E		000019A8	1040+	VST	V22, V1021
000019D2	07FB			1041+	BR	R11
000019D4				1042+RE21	DC	OF
000019D4				1043+	DROP	R5
000019D4	000000FF FF000000			1044	DC	XL16' 000000FF FF000000 000000FF FF000000' expected mask
000019DC	000000FF FF000000					
				1045		
				1046	VRI_A	VGBM, 0330
000019E8				1047+	DS	OFD
000019E8		000019E8		1048+	USING	*, R5
000019E8	00001A30			1049+T22	DC	A(X22)
000019EC	0016			1050+	DC	H' 22'
000019EE	00			1051+	DC	X' 00'
000019EF	0330			1052+	DC	XL2' 0330'
000019F1	E5C7C2D4 40404040			1053+	DC	CL8' VGBM
000019FC	00001A54			1054+	DC	A(RE22+16)
00001A00	00001A64			1055+	DC	A(RE22+32)
00001A04	00000010			1056+	DC	A(16)
00001A08	00001A44			1057+REA22	DC	A(RE22)
00001A10	00000000 00000000			1058+	DS	FD
00001A18	00000000 00000000			1059+V1022	DS	XL16
00001A20	00000000 00000000					
00001A28	00000000 00000000			1060+	DS	FD
				1061+*		gap
00001A30				1062+X22	DS	OF
00001A30	E760 8E98 0806		00001098	1063+	VL	V22, V1FUDGE
00001A36	E760 0330 0844			1064+	VGBM	V22, X' 0330'
00001A3C	E760 5030 080E		00001A18	1065+	VST	V22, V1022
00001A42	07FB			1066+	BR	R11
00001A44				1067+RE22	DC	OF
00001A44				1068+	DROP	R5
00001A44	00000000 0000FFFF			1069	DC	XL16' 00000000 0000FFFF 0000FFFF 00000000' expected mask
00001A4C	0000FFFF 00000000					
				1070		
				1071	VRI_A	VGBM, 3003

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001A58				1072+	DS	OFD	
00001A58		00001A58		1073+	USING	*, R5	base for test data and test routine
00001A58	00001AA0			1074+T23	DC	A(X23)	address of test routine
00001A5C	0017			1075+	DC	H' 23'	test number
00001A5E	00			1076+	DC	X' 00'	
00001A5F	3003			1077+	DC	XL2' 3003'	i2
00001A61	E5C7C2D4 40404040			1078+	DC	CL8' VGBM	instruction name
00001A6C	00001AC4			1079+	DC	A(RE23+16)	address of v2 source
00001A70	00001AD4			1080+	DC	A(RE23+32)	address of v3 source
00001A74	00000010			1081+	DC	A(16)	result length
00001A78	00001AB4			1082+REA23	DC	A(RE23)	result address
00001A80	00000000 00000000			1083+	DS	FD	gap
00001A88	00000000 00000000			1084+V1023	DS	XL16	V1 output
00001A90	00000000 00000000						
00001A98	00000000 00000000			1085+	DS	FD	gap
				1086+*			
00001AA0				1087+X23	DS	OF	
00001AA0	E760 8E98 0806		00001098	1088+	VL	V22, V1FUDGE	
00001AA6	E760 3003 0844			1089+	VGBM	V22, X' 3003'	test instruction (dest is a source)
00001AAC	E760 5030 080E		00001A88	1090+	VST	V22, V1023	save v1 output
00001AB2	07FB			1091+	BR	R11	return
00001AB4				1092+RE23	DC	OF	xl16 expected result
00001AB4				1093+	DROP	R5	
00001AB4	0000FFFF 00000000			1094	DC	XL16' 0000FFFF 00000000 00000000 0000FFFF'	expected mask
00001ABC	00000000 0000FFFF						
				1095			
				1096	VRI_A	VGBM, 3131	
00001AC8				1097+	DS	OFD	
00001AC8		00001AC8		1098+	USING	*, R5	base for test data and test routine
00001AC8	00001B10			1099+T24	DC	A(X24)	address of test routine
00001ACC	0018			1100+	DC	H' 24'	test number
00001ACE	00			1101+	DC	X' 00'	
00001ACF	3131			1102+	DC	XL2' 3131'	i2
00001AD1	E5C7C2D4 40404040			1103+	DC	CL8' VGBM	instruction name
00001ADC	00001B34			1104+	DC	A(RE24+16)	address of v2 source
00001AE0	00001B44			1105+	DC	A(RE24+32)	address of v3 source
00001AE4	00000010			1106+	DC	A(16)	result length
00001AE8	00001B24			1107+REA24	DC	A(RE24)	result address
00001AF0	00000000 00000000			1108+	DS	FD	gap
00001AF8	00000000 00000000			1109+V1024	DS	XL16	V1 output
00001B00	00000000 00000000						
00001B08	00000000 00000000			1110+	DS	FD	gap
				1111+*			
00001B10				1112+X24	DS	OF	
00001B10	E760 8E98 0806		00001098	1113+	VL	V22, V1FUDGE	
00001B16	E760 3131 0844			1114+	VGBM	V22, X' 3131'	test instruction (dest is a source)
00001B1C	E760 5030 080E		00001AF8	1115+	VST	V22, V1024	save v1 output
00001B22	07FB			1116+	BR	R11	return
00001B24				1117+RE24	DC	OF	xl16 expected result
00001B24				1118+	DROP	R5	
00001B24	0000FFFF 000000FF			1119	DC	XL16' 0000FFFF 000000FF 0000FFFF 000000FF'	expected mask
00001B2C	0000FFFF 000000FF						
				1120			
				1121	VRI_A	VGBM, 1313	
00001B38				1122+	DS	OFD	
00001B38		00001B38		1123+	USING	*, R5	base for test data and test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001B38	00001B80			1124+T25	DC	A(X25) address of test routine
00001B3C	0019			1125+	DC	H' 25' test number
00001B3E	00			1126+	DC	X' 00'
00001B3F	1313			1127+	DC	XL2' 1313' i2
00001B41	E5C7C2D4 40404040			1128+	DC	CL8' VGBM instruction name
00001B4C	00001BA4			1129+	DC	A(RE25+16) address of v2 source
00001B50	00001BB4			1130+	DC	A(RE25+32) address of v3 source
00001B54	00000010			1131+	DC	A(16) result length
00001B58	00001B94			1132+REA25	DC	A(RE25) result address
00001B60	00000000 00000000			1133+	DS	FD gap
00001B68	00000000 00000000			1134+V1025	DS	XL16 V1 output
00001B70	00000000 00000000					
00001B78	00000000 00000000			1135+	DS	FD gap
				1136+*		
00001B80				1137+X25	DS	0F
00001B80	E760 8E98 0806		00001098	1138+	VL	V22, V1FUDGE
00001B86	E760 1313 0844			1139+	VGBM	V22, X' 1313' test instruction (dest is a source)
00001B8C	E760 5030 080E		00001B68	1140+	VST	V22, V1025 save v1 output
00001B92	07FB			1141+	BR	R11 return
00001B94				1142+RE25	DC	0F xl16 expected result
00001B94				1143+	DROP	R5
00001B94	000000FF 0000FFFF			1144	DC	XL16' 000000FF 0000FFFF 000000FF 0000FFFF' expected mask
00001B9C	000000FF 0000FFFF					
				1145		
00001BA8				1146	VRI_A	VGBM, 0770
00001BA8		00001BA8		1147+	DS	0FD
00001BA8	00001BF0			1148+	USING	*, R5 base for test data and test routine
00001BAC	001A			1149+T26	DC	A(X26) address of test routine
00001BAE	00			1150+	DC	H' 26' test number
00001BAF	0770			1151+	DC	X' 00'
00001BB1	E5C7C2D4 40404040			1152+	DC	XL2' 0770' i2
00001BBC	00001C14			1153+	DC	CL8' VGBM instruction name
00001BC0	00001C24			1154+	DC	A(RE26+16) address of v2 source
00001BC4	00000010			1155+	DC	A(RE26+32) address of v3 source
00001BC8	00001C04			1156+	DC	A(16) result length
00001BD0	00000000 00000000			1157+REA26	DC	A(RE26) result address
00001BD8	00000000 00000000			1158+	DS	FD gap
00001BE0	00000000 00000000			1159+V1026	DS	XL16 V1 output
00001BE8	00000000 00000000					
				1160+	DS	FD gap
				1161+*		
00001BF0				1162+X26	DS	0F
00001BF0	E760 8E98 0806		00001098	1163+	VL	V22, V1FUDGE
00001BF6	E760 0770 0844			1164+	VGBM	V22, X' 0770' test instruction (dest is a source)
00001BFC	E760 5030 080E		00001BD8	1165+	VST	V22, V1026 save v1 output
00001C02	07FB			1166+	BR	R11 return
00001C04				1167+RE26	DC	0F xl16 expected result
00001C04				1168+	DROP	R5
00001C04	00000000 00FFFFFF			1169	DC	XL16' 00000000 00FFFFFF 00FFFFFF 00000000' expected mask
00001C0C	00FFFFFF 00000000					
				1170		
00001C18				1171	VRI_A	VGBM, 7007
00001C18		00001C18		1172+	DS	0FD
00001C18	00001C60			1173+	USING	*, R5 base for test data and test routine
00001C1C	001B			1174+T27	DC	A(X27) address of test routine
				1175+	DC	H' 27' test number



LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001C1E	00			1176+	DC	X' 00'
00001C1F	7007			1177+	DC	XL2' 7007' i2
00001C21	E5C7C2D4 40404040			1178+	DC	CL8' VGBM instruction name
00001C2C	00001C84			1179+	DC	A(RE27+16) address of v2 source
00001C30	00001C94			1180+	DC	A(RE27+32) address of v3 source
00001C34	00000010			1181+	DC	A(16) result length
00001C38	00001C74			1182+REA27	DC	A(RE27) result address
00001C40	00000000 00000000			1183+	DS	FD gap
00001C48	00000000 00000000			1184+V1027	DS	XL16 V1 output
00001C50	00000000 00000000					
00001C58	00000000 00000000			1185+	DS	FD gap
				1186+*		
00001C60				1187+X27	DS	0F
00001C60	E760 8E98 0806		00001098	1188+	VL	V22, V1FUDGE
00001C66	E760 7007 0844			1189+	VGBM	V22, X' 7007' test instruction (dest is a source)
00001C6C	E760 5030 080E		00001C48	1190+	VST	V22, V1027 save v1 output
00001C72	07FB			1191+	BR	R11 return
00001C74				1192+RE27	DC	0F xl16 expected result
00001C74				1193+	DROP	R5
00001C74	00FFFFFF 00000000			1194	DC	XL16' 00FFFFFF 00000000 00000000 00FFFFFF' expected mask
00001C7C	00000000 00FFFFFF					
				1195		
				1196	VRI_A	VGBM, 7171
00001C88				1197+	DS	0FD
00001C88		00001C88		1198+	USING	*, R5 base for test data and test routine
00001C88	00001CD0			1199+T28	DC	A(X28) address of test routine
00001C8C	001C			1200+	DC	H' 28' test number
00001C8E	00			1201+	DC	X' 00'
00001C8F	7171			1202+	DC	XL2' 7171' i2
00001C91	E5C7C2D4 40404040			1203+	DC	CL8' VGBM instruction name
00001C9C	00001CF4			1204+	DC	A(RE28+16) address of v2 source
00001CA0	00001D04			1205+	DC	A(RE28+32) address of v3 source
00001CA4	00000010			1206+	DC	A(16) result length
00001CA8	00001CE4			1207+REA28	DC	A(RE28) result address
00001CB0	00000000 00000000			1208+	DS	FD gap
00001CB8	00000000 00000000			1209+V1028	DS	XL16 V1 output
00001CC0	00000000 00000000					
00001CC8	00000000 00000000			1210+	DS	FD gap
				1211+*		
00001CD0				1212+X28	DS	0F
00001CD0	E760 8E98 0806		00001098	1213+	VL	V22, V1FUDGE
00001CD6	E760 7171 0844			1214+	VGBM	V22, X' 7171' test instruction (dest is a source)
00001CDC	E760 5030 080E		00001CB8	1215+	VST	V22, V1028 save v1 output
00001CE2	07FB			1216+	BR	R11 return
00001CE4				1217+RE28	DC	0F xl16 expected result
00001CE4				1218+	DROP	R5
00001CE4	00FFFFFF 000000FF			1219	DC	XL16' 00FFFFFF 000000FF 00FFFFFF 000000FF' expected mask
00001CEC	00FFFFFF 000000FF					
				1220		
				1221	VRI_A	VGBM, 1717
00001CF8				1222+	DS	0FD
00001CF8		00001CF8		1223+	USING	*, R5 base for test data and test routine
00001CF8	00001D40			1224+T29	DC	A(X29) address of test routine
00001CFC	001D			1225+	DC	H' 29' test number
00001CFE	00			1226+	DC	X' 00'
00001CFF	1717			1227+	DC	XL2' 1717' i2



[illegible]



LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				1293	*****
				1294	*            Register equates
				1295	*****
		00000000	00000001	1297 R0	EQU 0
		00000001	00000001	1298 R1	EQU 1
		00000002	00000001	1299 R2	EQU 2
		00000003	00000001	1300 R3	EQU 3
		00000004	00000001	1301 R4	EQU 4
		00000005	00000001	1302 R5	EQU 5
		00000006	00000001	1303 R6	EQU 6
		00000007	00000001	1304 R7	EQU 7
		00000008	00000001	1305 R8	EQU 8
		00000009	00000001	1306 R9	EQU 9
		0000000A	00000001	1307 R10	EQU 10
		0000000B	00000001	1308 R11	EQU 11
		0000000C	00000001	1309 R12	EQU 12
		0000000D	00000001	1310 R13	EQU 13
		0000000E	00000001	1311 R14	EQU 14
		0000000F	00000001	1312 R15	EQU 15
				1314	*****
				1315	*            Register equates
				1316	*****
		00000000	00000001	1318 V0	EQU 0
		00000001	00000001	1319 V1	EQU 1
		00000002	00000001	1320 V2	EQU 2
		00000003	00000001	1321 V3	EQU 3
		00000004	00000001	1322 V4	EQU 4
		00000005	00000001	1323 V5	EQU 5
		00000006	00000001	1324 V6	EQU 6
		00000007	00000001	1325 V7	EQU 7
		00000008	00000001	1326 V8	EQU 8
		00000009	00000001	1327 V9	EQU 9
		0000000A	00000001	1328 V10	EQU 10
		0000000B	00000001	1329 V11	EQU 11
		0000000C	00000001	1330 V12	EQU 12
		0000000D	00000001	1331 V13	EQU 13
		0000000E	00000001	1332 V14	EQU 14
		0000000F	00000001	1333 V15	EQU 15
		00000010	00000001	1334 V16	EQU 16
		00000011	00000001	1335 V17	EQU 17
		00000012	00000001	1336 V18	EQU 18
		00000013	00000001	1337 V19	EQU 19
		00000014	00000001	1338 V20	EQU 20
		00000015	00000001	1339 V21	EQU 21



SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES														
BEGIN	I	00000200	2	151	117	147	148	149											
CTLRO	F	00000484	4	346	161	162	163	164											
DECNUM	C	00001076	16	397	260	262	268	270											
E7TEST	4	00000000	72	411	210														
E7TESTS	F	00001D6C	4	1254	203														
EDIT	X	0000104A	18	392	261	269													
ENDTEST	U	00000318	1	246	208														
E0J	I	00000468	4	336	196	249													
E0JPSW	D	00000458	8	334	336														
FAILCONT	U	00000308	1	236															
FAILED	F	00001000	4	374	238	247													
FAILMSG	U	00000304	1	230	220														
FAILPSW	D	00000470	8	338	340														
FAILTEST	I	00000480	4	340	250														
FB0001	F	00000280	8	180	184	185	187												
I2	X	00000007	2	415	267														
IMAGE	1	00000000	7664	0															
K	U	00000400	1	358	359	360	361												
K64	U	00010000	1	360															
MB	U	00100000	1	361															
MSG	I	000003A0	4	296	195	279													
MSGCMD	C	000003EE	9	326	309	310													
MSGMSG	C	000003F7	95	327	303	324	301												
MSGMVC	I	000003E8	6	324	307														
MSGOK	I	000003B6	2	305	302														
MSGRET	I	000003D6	4	320	313	316													
MSGSAVE	F	000003DC	4	323	299	320													
NEXTE6	U	000002D4	1	205	223	241													
OPNAME	C	00000009	8	417	265														
PAGE	U	00001000	1	359															
PRT3	C	00001060	18	395	261	262	263	269	270	271									
PRTI2	C	00001044	5	385	271														
PRTLIN	C	00001008	16	380	387	278													
PRTLNG	U	00000042	1	387	277														
PRTNAME	C	00001033	8	383	265														
PRTNUM	C	00001018	3	381	263														
R0	U	00000000	1	1297	111	161	164	184	186	187	188	193	212	213	237	238	276		
					277	280	296	299	301	303	305	320							
R1	U	00000001	1	1298	194	218	219	247	248	278	310	324							
R10	U	0000000A	1	1307	149	158	159												
R11	U	0000000B	1	1308	215	216	538	563	588	613	638	663	688	713	738	763	788		
					813	838	863	888	913	938	963	991	1016	1041	1066	1091	1116		
					1141	1166	1191	1216	1241										
R12	U	0000000C	1	1309	203	206	222	240											
R13	U	0000000D	1	1310															
R14	U	0000000E	1	1311															
R15	U	0000000F	1	1312	231	256	283	284											
R2	U	00000002	1	1299	195	259	260	267	268	276	279	280	297	299	305	306	307		
					309	315	320	321											
R3	U	00000003	1	1300															
R4	U	00000004	1	1301															
R5	U	00000005	1	1302	206	207	210	257	282	520	540	545	565	570	590	595	615		
					620	640	645	665	670	690	695	715	720	740	745	765	770		
					790	795	815	820	840	845	865	870	890	895	915	920	940		
					945	965	973	993	998	1018	1023	1043	1048	1068	1073	1093	1098		
					1118	1123	1143	1148	1168	1173	1193	1198	1218	1223	1243				

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES				
R6	U	00000006	1	1303					
R7	U	00000007	1	1304					
R8	U	00000008	1	1305	147	151	152	153	155
R9	U	00000009	1	1306	148	155	156	158	
RE1	F	00001114	4	539	526	527	529		
RE10	F	00001504	4	764	751	752	754		
RE11	F	00001574	4	789	776	777	779		
RE12	F	000015E4	4	814	801	802	804		
RE13	F	00001654	4	839	826	827	829		
RE14	F	000016C4	4	864	851	852	854		
RE15	F	00001734	4	889	876	877	879		
RE16	F	000017A4	4	914	901	902	904		
RE17	F	00001814	4	939	926	927	929		
RE18	F	00001884	4	964	951	952	954		
RE19	F	000018F4	4	992	979	980	982		
RE2	F	00001184	4	564	551	552	554		
RE20	F	00001964	4	1017	1004	1005	1007		
RE21	F	000019D4	4	1042	1029	1030	1032		
RE22	F	00001A44	4	1067	1054	1055	1057		
RE23	F	00001AB4	4	1092	1079	1080	1082		
RE24	F	00001B24	4	1117	1104	1105	1107		
RE25	F	00001B94	4	1142	1129	1130	1132		
RE26	F	00001C04	4	1167	1154	1155	1157		
RE27	F	00001C74	4	1192	1179	1180	1182		
RE28	F	00001CE4	4	1217	1204	1205	1207		
RE29	F	00001D54	4	1242	1229	1230	1232		
RE3	F	000011F4	4	589	576	577	579		
RE4	F	00001264	4	614	601	602	604		
RE5	F	000012D4	4	639	626	627	629		
RE6	F	00001344	4	664	651	652	654		
RE7	F	000013B4	4	689	676	677	679		
RE8	F	00001424	4	714	701	702	704		
RE9	F	00001494	4	739	726	727	729		
REA1	A	000010D8	4	529					
REA10	A	000014C8	4	754					
REA11	A	00001538	4	779					
REA12	A	000015A8	4	804					
REA13	A	00001618	4	829					
REA14	A	00001688	4	854					
REA15	A	000016F8	4	879					
REA16	A	00001768	4	904					
REA17	A	000017D8	4	929					
REA18	A	00001848	4	954					
REA19	A	000018B8	4	982					
REA2	A	00001148	4	554					
REA20	A	00001928	4	1007					
REA21	A	00001998	4	1032					
REA22	A	00001A08	4	1057					
REA23	A	00001A78	4	1082					
REA24	A	00001AE8	4	1107					
REA25	A	00001B58	4	1132					
REA26	A	00001BC8	4	1157					
REA27	A	00001C38	4	1182					
REA28	A	00001CA8	4	1207					
REA29	A	00001D18	4	1232					
REA3	A	000011B8	4	579					

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	
REA4	A	00001228	4	604		
REA5	A	00001298	4	629		
REA6	A	00001308	4	654		
REA7	A	00001378	4	679		
REA8	A	000013E8	4	704		
REA9	A	00001458	4	729		
READDR	A	00000020	4	421	218	
REG2LOW	U	000000DD	1	364		
REG2PATT	U	AABBCCDD	1	363		
RELEN	A	0000001C	4	420		
RPTDWSAV	D	00000390	8	289	276	280
RPTERROR	I	00000326	4	256	231	
RPTSAVE	F	00000388	4	286	256	283
RPTSVR5	F	0000038C	4	287	257	282
SKL0001	U	0000004E	1	177	193	
SKT0001	C	0000022A	20	174	177	194
SVOLDPSW	U	00000140	0	113		
T1	A	000010B8	4	521	1257	
T10	A	000014A8	4	746	1266	
T11	A	00001518	4	771	1267	
T12	A	00001588	4	796	1268	
T13	A	000015F8	4	821	1269	
T14	A	00001668	4	846	1270	
T15	A	000016D8	4	871	1271	
T16	A	00001748	4	896	1272	
T17	A	000017B8	4	921	1273	
T18	A	00001828	4	946	1274	
T19	A	00001898	4	974	1275	
T2	A	00001128	4	546	1258	
T20	A	00001908	4	999	1276	
T21	A	00001978	4	1024	1277	
T22	A	000019E8	4	1049	1278	
T23	A	00001A58	4	1074	1279	
T24	A	00001AC8	4	1099	1280	
T25	A	00001B38	4	1124	1281	
T26	A	00001BA8	4	1149	1282	
T27	A	00001C18	4	1174	1283	
T28	A	00001C88	4	1199	1284	
T29	A	00001CF8	4	1224	1285	
T3	A	00001198	4	571	1259	
T4	A	00001208	4	596	1260	
T5	A	00001278	4	621	1261	
T6	A	000012E8	4	646	1262	
T7	A	00001358	4	671	1263	
T8	A	000013C8	4	696	1264	
T9	A	00001438	4	721	1265	
TESTING	F	00001004	4	375	213	
TNUM	H	00000004	2	413	212	259
TSUB	A	00000000	4	412	215	
TTABLE	F	00001D6C	4	1256		
V0	U	00000000	1	1318		
V1	U	00000001	1	1319		
V10	U	0000000A	1	1328		
V11	U	0000000B	1	1329		
V12	U	0000000C	1	1330		
V13	U	0000000D	1	1331		



SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES					
V2ADDR	A	00000014	4	418						
V3	U	00000003	1	1321						
V30	U	0000001E	1	1348						
V31	U	0000001F	1	1349						
V3ADDR	A	00000018	4	419						
V4	U	00000004	1	1322						
V5	U	00000005	1	1323						
V6	U	00000006	1	1324						
V7	U	00000007	1	1325						
V8	U	00000008	1	1326						
V9	U	00000009	1	1327						
X0001	U	000002A8	1	183	171	184				
X1	F	00001100	4	534	521					
X10	F	000014F0	4	759	746					
X11	F	00001560	4	784	771					
X12	F	000015D0	4	809	796					
X13	F	00001640	4	834	821					
X14	F	000016B0	4	859	846					
X15	F	00001720	4	884	871					
X16	F	00001790	4	909	896					
X17	F	00001800	4	934	921					
X18	F	00001870	4	959	946					
X19	F	000018E0	4	987	974					
X2	F	00001170	4	559	546					
X20	F	00001950	4	1012	999					
X21	F	000019C0	4	1037	1024					
X22	F	00001A30	4	1062	1049					
X23	F	00001AA0	4	1087	1074					
X24	F	00001B10	4	1112	1099					
X25	F	00001B80	4	1137	1124					
X26	F	00001BF0	4	1162	1149					
X27	F	00001C60	4	1187	1174					
X28	F	00001CD0	4	1212	1199					
X29	F	00001D40	4	1237	1224					
X3	F	000011E0	4	584	571					
X4	F	00001250	4	609	596					
X5	F	000012C0	4	634	621					
X6	F	00001330	4	659	646					
X7	F	000013A0	4	684	671					
X8	F	00001410	4	709	696					
X9	F	00001480	4	734	721					
XC0001	U	000002D0	1	197	189					
ZVE7TST	J	00000000	7664	110	113	115	119	123	373	111
=A(E7TESTS)	A	00000490	4	351	203					
=AL2(L' MSGMSG)	R	0000049A	2	354	301					
=F' 1'	F	00000494	4	352	237					
=F' 64'	F	0000048C	4	350	188					
=H' 0'	H	00000498	2	353	296					





DESC	SYMBOL	SIZE	POS	ADDR
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**Entry: 0**

Image	IMAGE	7664	0000-1DEF	0000-1DEF
Region		7664	0000-1DEF	0000-1DEF
CSECT	ZVE7TST	7664	0000-1DEF	0000-1DEF

STMT	FILE NAME
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1	/home/tn529/sharedvfp/tests/zvector-e7-07-VGBM asm
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**\*\* NO ERRORS FOUND \*\***